

WaferPro Express
2016.04

WaferPro Express 2016_04 Hotfix Release Notes

Notices

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WaferPro Express 2016.04 Hotfix 1 Release Notes

Release: Sep 20, 2016

Version

721.hf1

Enhancements

- Supports more than 50,000 data points in A-LFNA RTN measurements.
- Added support for MCSMU (Medium Current SMU) in B1500.

Issues Addressed

- Resolved memory overflow issues arising from larger on-wafer A-LFNA test plans.
- Repaired several A-LFNA Viewer issues and improvements.
- Fixed a measurement error when using some older B1500A instruments in conjunction with A-LFNA.
- Resolved error when connecting to UF3000/P8 probers.
- Repaired issue when reloading old log file in WaferPro Log View window.
- Repaired issue with S-Parameter measurements with a PNA-X that does not support receiver leveling.

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